

Contents

1	Revis	sion History1	
	1.1	Revision J1	
	1.2	Revision I1	
	1.3	Revision H1	
	1.4	Revision G1	
	1.5	Revision F1	
	1.6	Revision E1	
	1.7	Revision D1	
	1.8	Revision C1	
	1.9	Revision B 2	
	1.10	Revision A2	
2	Prod	uct Overview	
-		Features	
	2.2	Benefits	
	2.3	Applications	
2		wight Charliesting	
5		rical Specifications	
	3.1	Absolute Maximum Ratings 4	
	3.2	Electrical Performance	
	3.3	Typical Performance Curves	l
	3.4	Reverse Recovery Overview	
4	Pack	age Specification	
		Package Outline Drawing	



1 Revision History

The revision history describes the changes that were implemented in the document. The changes are listed by revision, starting with the most current publication.

1.1 Revision J

Revision J was published in March 2017. The following is a summary of the changes in revision J of this document.

- Updated bullets in Product Overview section.
- Removed square wave 50% duty cycle in the Absolute Maximum Ratings table.

1.2 Revision I

Revision I was published in January 2017. The following is a summary of the changes in revision I of this document.

• Updated features section.

1.3 Revision H

Revision H was published in July 2016. The following is a summary of the changes in revision H of this document.

• Updated K pack dimensions.

1.4 Revision G

Revision G was published in January 2016. The following is a summary of the changes in revision G of this document.

Revised the K pack outline.

1.5 Revision F

Revision F was published in May 2011. The following is a summary of the changes in revision F of this document.

• Updated B pack information changing the maximum lead thickness.

1.6 Revision E

Revision E was published in March 2009. The following is a summary of the changes in revision E of this document.

• Updated K pack and removed thermal ladder.

1.7 Revision D

Revision D was published in November 2008. The following is a summary of the changes in revision D of this document.

- Updated K pack drawing outline in the Product Overview section.
- Changed APT references to Microsemi.

1.8 Revision C

Revision C was published in October 2006. There were no changes to the technical content in revision C of this document.



1.9 Revision B

Revision B was published in August 2005. The following is a summary of the changes in revision B of this document.

• The IRM value in Table 2 Static Characteristics was updated.

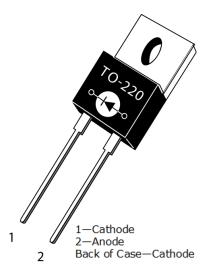
1.10 Revision A

Revision A was published in May 2005. It is the first publication of this document.



2 Product Overview

This section outlines the product overview for the APT15DQ120KG device.



2.1 Features

The following are key features of the APT15DQ120KG device:

- Ultrafast recovery times
- Soft recovery characteristics
- Low forward voltage
- Low leakage current
- Avalanche energy rated
- RoHS compliant
- AEC-Q101 qualified

2.2 Benefits

The following are benefits of the APT15DQ120KG device:

- Higher switching frequency
- Low switching losses
- Low noise (EMI) switching
- Higher reliability systems
- Increased system power density

2.3 Applications

The APT15DQ120KG device is designed for the following applications:

- Power factor correction (PFC)
- Anti-parallel diode
 - Switch-mode power supply
 - Inverters/converters
 - Motor controllers
- Freewheeling diode
 - Switch-mode power supply
 - Inverters/converters
- Snubber/clamp diode



3 Electrical Specifications

This section details the electrical specifications for the APT15DQ120KG device.

3.1 Absolute Maximum Ratings

The following table shows the absolute maximum ratings for the APT15DQ120KG device.

All ratings taken at Tc = 25 °C, unless otherwise specified.

Table 1 • Absolute Maximum Ratings

Symbol	Parameter	Ratings	Unit
VR	Maximum DC reverse voltage	1200	V
VRRM	Maximum peak repetitive reverse voltage	1200	
VRWM	Maximum working peak reverse voltage	1200	
IF(AV)	Maximum average forward current (Tc = 127 °C, duty cycle = 0.5)	15	Α
F(RMS)	RMS forward current	29	
IFSM	Non-repetitive forward surge current (T _J = 45 °C, 8.3 ms)	110	
Eavl	Avalanche energy (1 A, 40 mH)	20	mJ
TJ, TSTG	Operating and storage temperature range	-55 to 175	°C
Tι	Lead temperature for 10 seconds	300	

3.2 Electrical Performance

-

The following table shows the static characteristics of the APT15DQ120KG device.

Table 2 • Static Characteristics

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
VF	Forward Voltage	IF = 15 A		2.8	3.3	V
		IF = 30 A		3.4		-
		I⊧ = 15 A, Tı = 125 °C		2.45		_
Irm	Maximum reverse leakage current	V _R = 1200 V			100	μA
		V _R = 1200 V, T _J = 125 °C			500	=
C	Junction capacitance	V _R = 200 V		17		pF



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The following table shows the dynamic characteristics of the APT15DQ120KG device.

Symbol	Characteristic	Test Conditions	Min	Тур	Max	Unit
trr	Reverse recovery time	IF = 1 A diF/dt = -100 A/μs VR = 30 V TJ = 25 °C		21		ns
trr	Reverse recovery time	I⊧ = 15 A		240		_
Qrr	Reverse recovery change	di⊧/dt = −200 A/μs, V _R = 800 V		260		nC
Irrm	Maximum reverse recovery current	$T_{J} = 25 \ ^{\circ}\text{C}$		3		А
trr	Reverse recovery time	IF = 15 A		290		ns
Qrr	Reverse recovery change	di⊧/dt = −200 A/μs V _R = 800 V		960		nC
Irrm	Maximum reverse recovery current	TJ = 125 °C		6		А
trr	Reverse recovery time	IF = 15 A		130		ns
Qrr	Reverse recovery change	di _F /dt = -1000 A/μs V _R = 800 V		1340		nC
Irrm	Maximum reverse recovery current	TJ = 125 °C		19		А

Table 3 • Dynamic Characteristics

The following table shows the thermal and mechanical characteristics of the APT15DQ120KG device.

Table 4 • Thermal and Mechanical Characteristics

Symbol	Characteristic	Min	Тур	Max	Unit
Rejc	Junction-to-case thermal resistance			1.18	°C/W
WT	Package weight		0.07		OZ
			1.9		g
Torque	Maximum mounting torque			10	lb-in
				1.1	N-m



3.3 Typical Performance Curves

This section shows the typical performance curves for the APT15DQ120KG device.

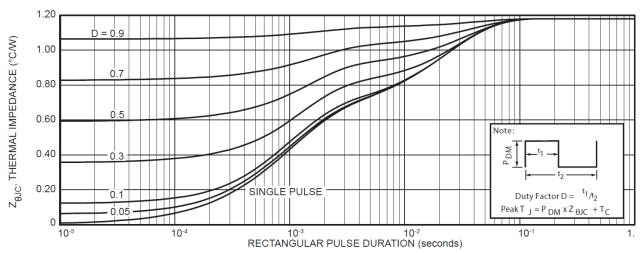


Figure 1 • Maximum Transient Thermal Impedance



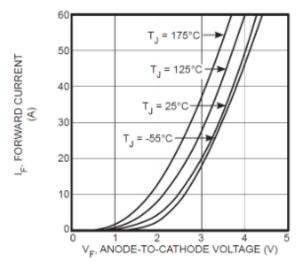
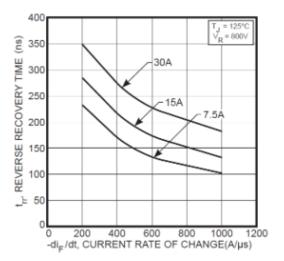


Figure 3 • trr vs. Current Rate of Change





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Figure 4 • Qrr vs. Current Rate of Change

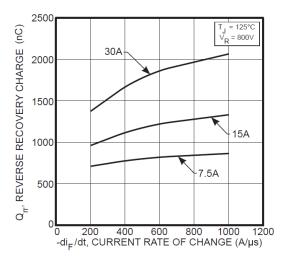


Figure 6 • Dynamic Parameters vs. Junction

Temperature

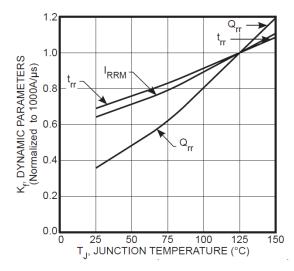


Figure 8 • Junction Capacitance vs. Reverse Voltage

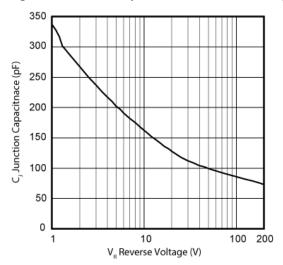


Figure 5 • IRRM vs. Current Rate of Change

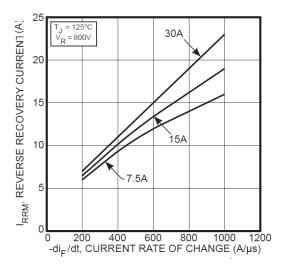
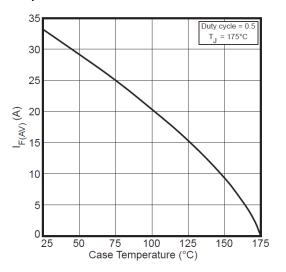


Figure 7 • Maximum Average Forward Current vs. Case Temperature





3.4 Reverse Recovery Overview

The following figures illustrate the reverse recovery testing and measurement information for the APT15DQ120KG device.

Figure 9 • Diode Test Circuit

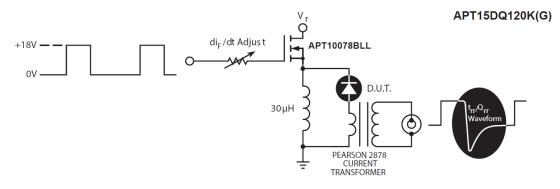


Figure 10 • Diode Reverse Recovery Waveform Definition

I_F - Forward Conduction Current
 di_F/dt - Rate of Diode Current Change Through Zero Crossing.
 I_{RRM} - Maximum Reverse Recovery Current
 t_{rr} - Reverse Recovery Time measured from zero crossing where diode current goes from positive to negative, to the point at which the straight line through I_{RRM} and 0.25, I_{RRM} passes through zero.
 Q_{rr} - Area Under the Curve Defined by I_{RRM} and t_{RR}.



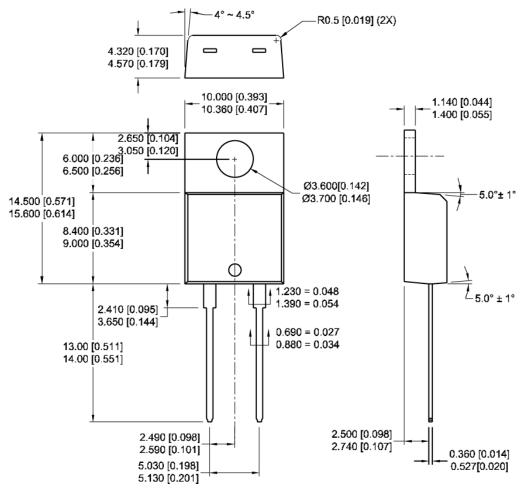
4 Package Specification

This section outlines the package specification for the APT15DQ120KG device.

4.1 Package Outline Drawing

This section details the TO-220 package drawing of the APT15DQ120KG device. Dimensions are in millimeters and (inches).

Figure 11 • Package Outline Drawing







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Microsemi Corporate Headquarters One Enterprise, Aliso Viejo, CA 92656 USA Within the USA: +1 (800) 713-4113 Outside the USA: +1 (949) 380-6100 Fax: +1 (949) 215-4996 Email: sales.support@microsemi.com

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